N-Channel 60 V (D-S) MOSFET

PRODUCT SUMMARY

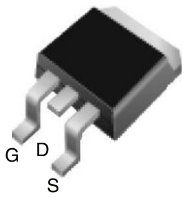
V_{DS} (V)	$R_{DS(on)}$ (Ω)	I_D (A)[a, e]	Q_g (Max)
60	0.023 at $V_{GS} = 10$ V	50	66 nC
	0.027 at $V_{GS} = 4.5$ V	40	

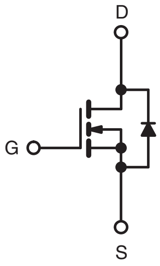
FEATURES

- **Halogen-free According to IEC 61249-2-21 Definition**
- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Logic-Level Gate Drive
- Fast Switching
- Compliant to RoHS Directive 2002/95/EC

RoHS*
COMPLIANT
HALOGEN
FREE
Available

D²PAK (TO-263)





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_C = 25$ °C, unless otherwise noted)

PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V_{DS}	60	V
Gate-Source Voltage			V_{GS}	± 10	
Continuous Drain Current[f]	V_{GS} at 10 V	$T_C = 25$ °C	I_D	50	A
Continuous Drain Current		$T_C = 100$ °C		36	
Pulsed Drain Current[a]			I_{DM}	200	
Linear Derating Factor				1.0	W/°C
Linear Derating Factor (PCB Mount)[e]				0.025	
Single Pulse Avalanche Energy[b]			E_{AS}	400	mJ
Maximum Power Dissipation	$T_C = 25$ °C		P_D	150	W
Maximum Power Dissipation (PCB Mount)[e]	$T_A = 25$ °C			3.7	
Peak Diode Recovery dV/dt[c]			dV/dt	4.5	V/ns
Operating Junction and Storage Temperature Range			T_J, T_{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)[d]	for 10 s			300[d]	

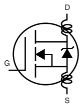
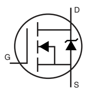
Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. $V_{DD} = 25$ V, starting $T_J = 25$ °C, L = 179 μH, $R_g = 25$ Ω, $I_{AS} = 51$ A (see fig. 12).
c. $I_{SD} \leq 51$ A, dI/dt ≤ 250 A/μs, $V_{DD} \leq V_{DS}$, $T_J \leq 175$ °C.
d. 1.6 mm from case.
e. When mounted on 1" square PCB (FR-4 or G-10 material).
f. Current limited by the package, (die current = 51 A).

THERMAL RESISTANCE RATINGS				
PARAMETER	**SYMBOL**	**TYP.**	**MAX.**	**UNIT**
Maximum Junction-to-Ambient	R_{thJA}	-	62	°C/W
Maximum Junction-to-Ambient (PCB Mount)[a]	R_{thJA}	-	40	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS (T_J = 25 °C, unless otherwise noted)						
PARAMETER	**SYMBOL**	**TEST CONDITIONS**	**MIN.**	**TYP.**	**MAX.**	**UNIT**
Static						
Drain-Source Breakdown Voltage	V_{DS}	V_{GS} = 0, I_D = 250 μA	60	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, I_D = 1 mA	-	0.070	-	V/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 250 μA	1.0	-	3.0	V
Gate-Source Leakage	I_{GSS}	V_{GS} = ± 10 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 60 V, V_{GS} = 0 V	-	-	25	μA
		V_{DS} = 48 V, V_{GS} = 0 V, T_J = 150 °C	-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	V_{GS} = 10 V, I_D = 21 A[b]	-	23	-	Ω
		V_{GS} = 4.5 V, I_D = 15 A[b]	-	27	-	
Forward Transconductance	g_{fs}	V_{DS} = 25 V, I_D = 21A[b]	23	-	-	S
Dynamic						
Input Capacitance	C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1.0 MHz, see fig. 5	-	3000	-	pF
Output Capacitance	C_{oss}		-	1000	-	
Reverse Transfer Capacitance	C_{rss}		-	200	-	
Total Gate Charge	Q_g	V_{GS} = 5.0 V, I_D = 51 A, V_{DS} = 48 V, see fig. 6 and 13[b]	-	60	-	nC
Gate-Source Charge	Q_{gs}		-	10	-	
Gate-Drain Charge	Q_{gd}		-	40	-	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = 30 V, I_D = 51 A, R_g = 4.6 Ω, R_D = 0.56 Ω, see fig. 10[b]	-	17	-	ns
Rise Time	t_r		-	230	-	
Turn-Off Delay Time	$t_{d(off)}$		-	42	-	
Fall Time	t_f		-	110	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact 	-	4.5	-	nH
Internal Source Inductance	L_S		-	7.5	-	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode 	-	-	50[c]	A
Pulsed Diode Forward Current[a]	I_{SM}		-	-	200	
Body Diode Voltage	V_{SD}	T_J = 25 °C, I_S = 51 A, V_{GS} = 0 V[b]	-	-	2.5	V
Body Diode Reverse Recovery Time	t_{rr}	T_J = 25 °C, I_F = 51 A, dI/dt = 100 A/μs[b]	-	130	180	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	0.84	1.3	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.
c. Current limited by the package, (Die Current = 51 A).

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

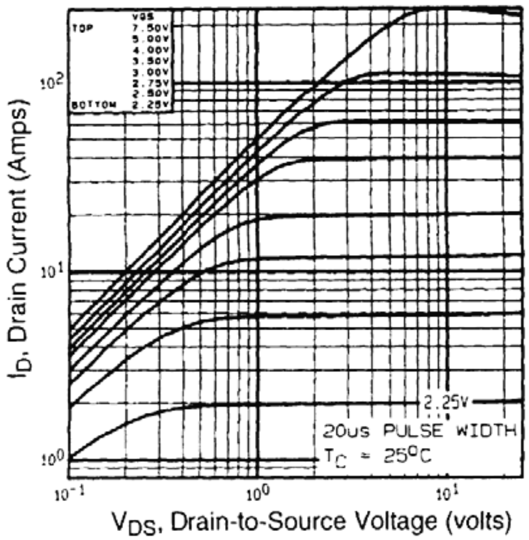


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

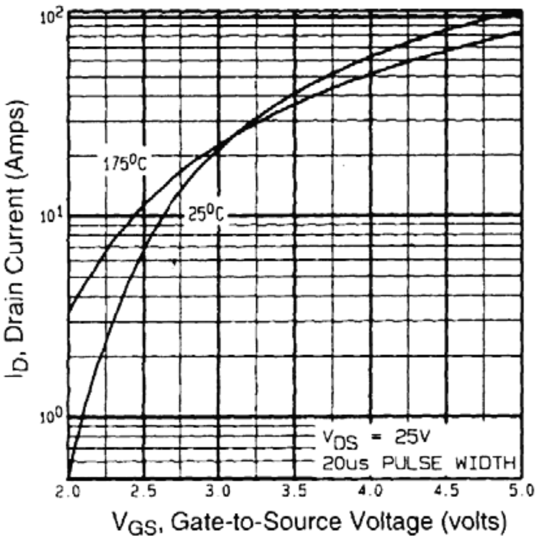


Fig. 3 - Typical Transfer Characteristics

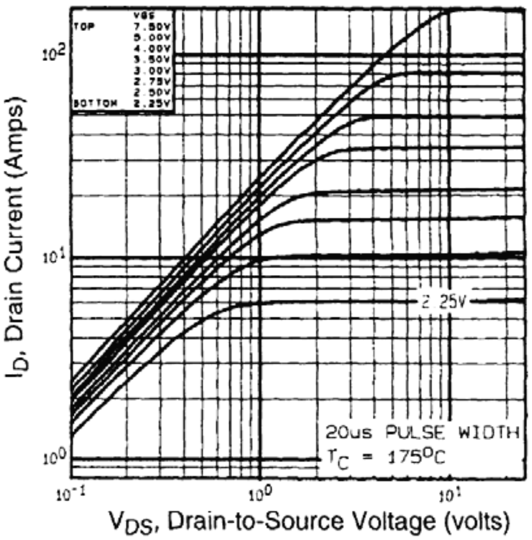


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

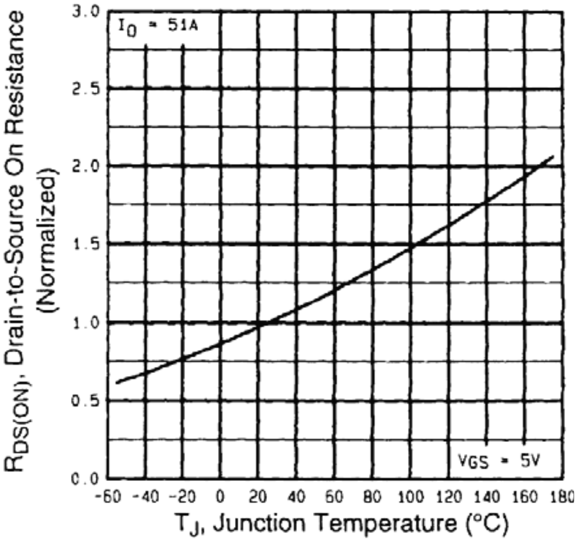


Fig. 4 - Normalized On-Resistance vs. Temperature

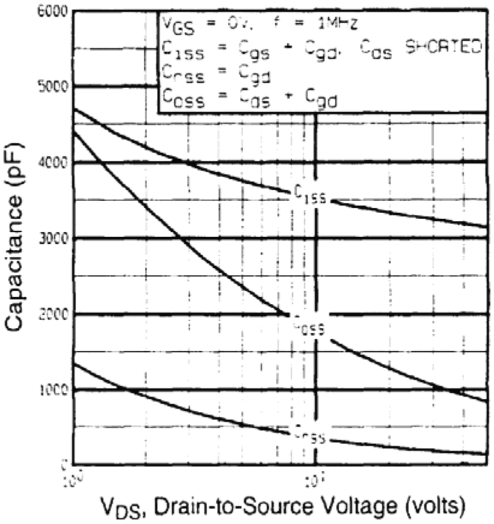


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

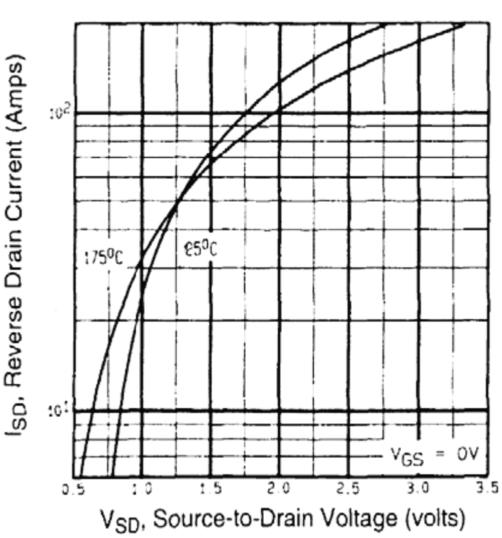


Fig. 7 - Typical Source-Drain Diode Forward Voltage

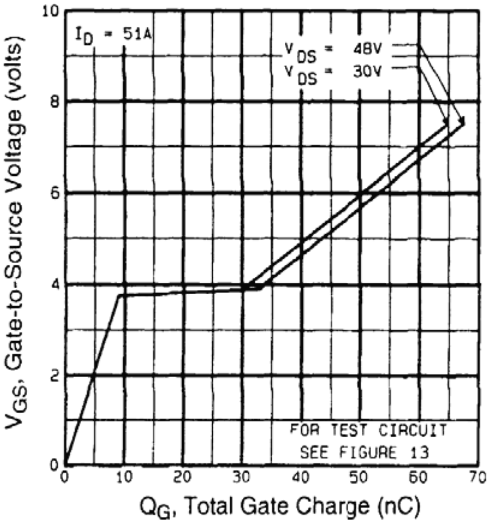


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

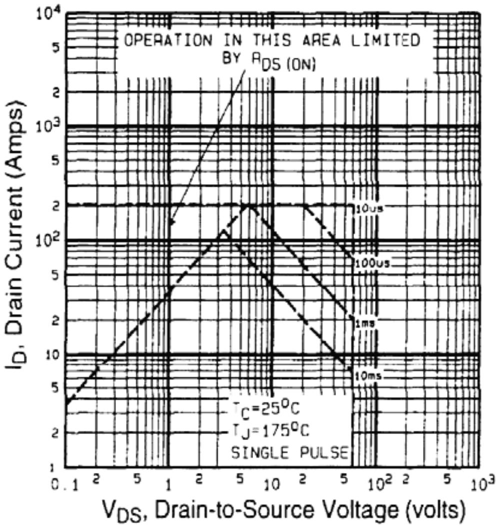


Fig. 8 - Maximum Safe Operating Area

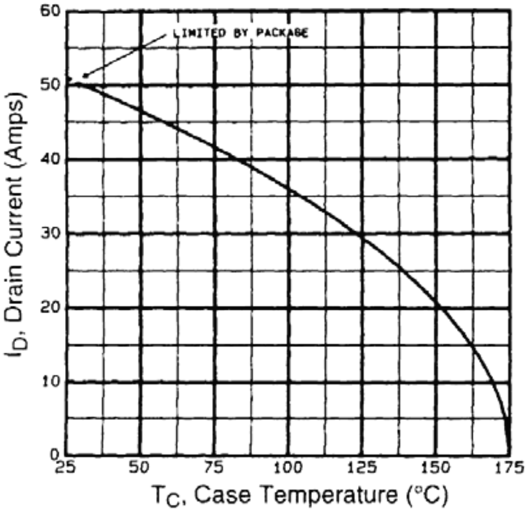


Fig. 9 - Maximum Drain Current vs. Case Temperature

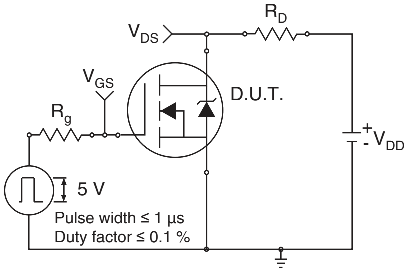


Fig. 10a - Switching Time Test Circuit

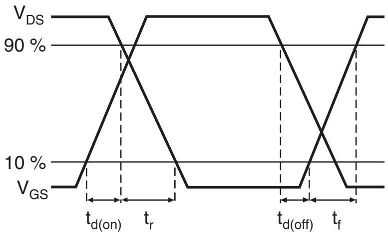


Fig. 10b - Switching Time Waveforms

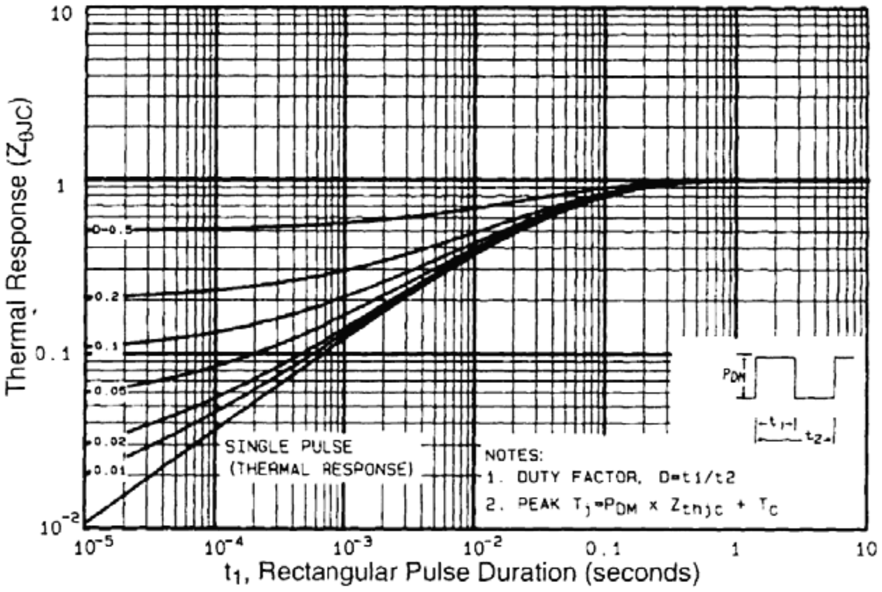


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

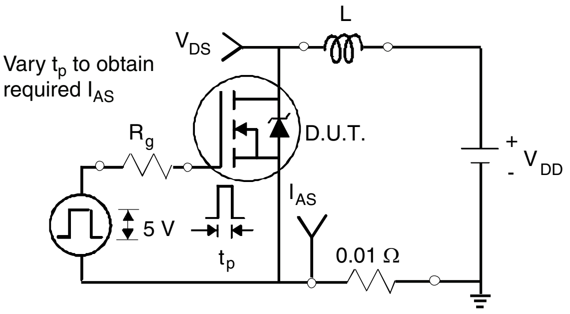


Fig. 12a - Unclamped Inductive Test Circuit

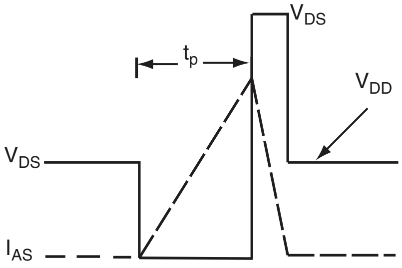


Fig. 12b - Unclamped Inductive Waveforms

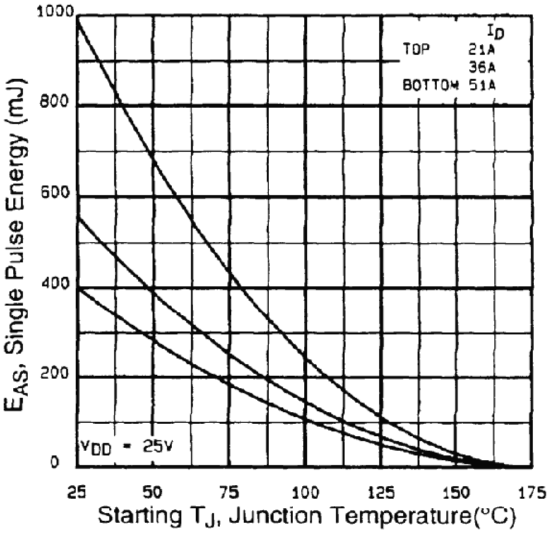


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

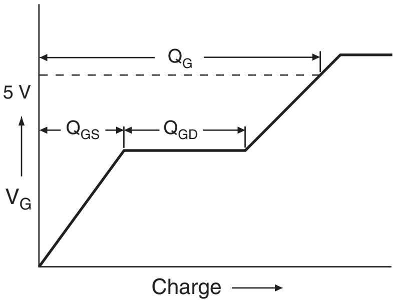


Fig. 13a - Basic Gate Charge Waveform

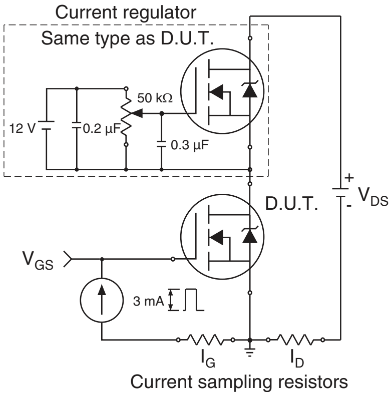
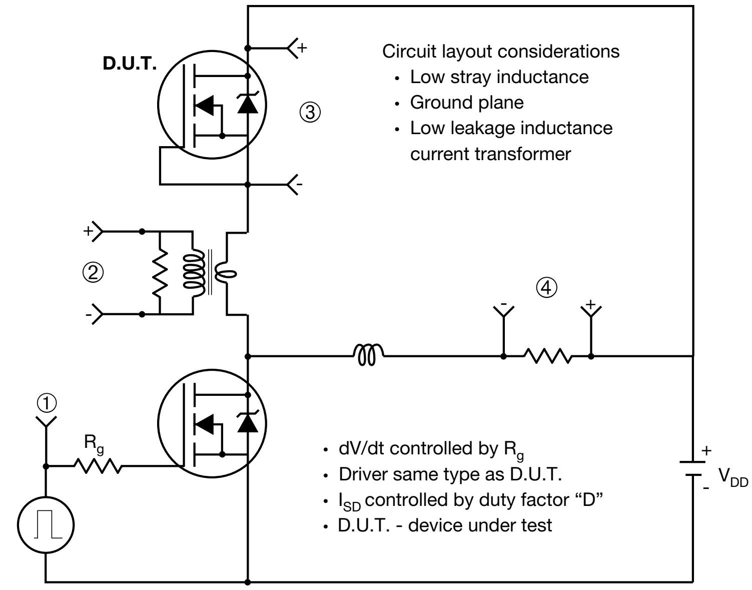
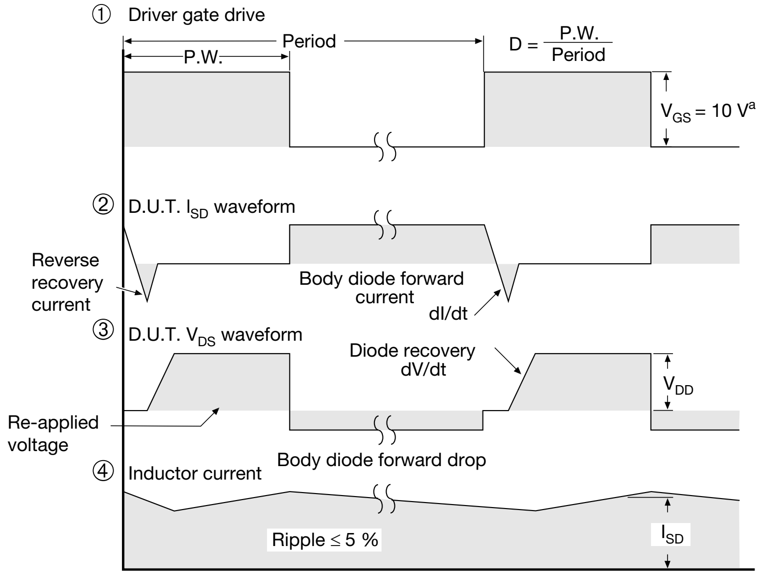


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



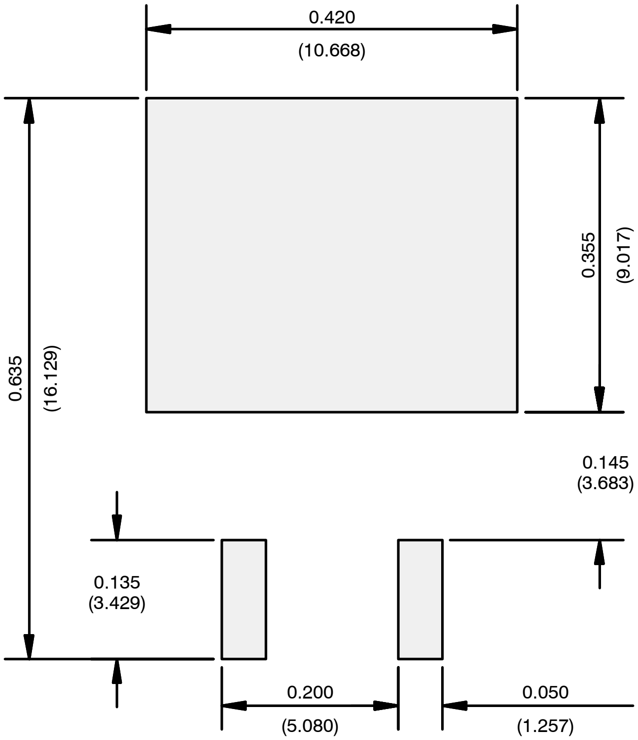


Note

a. V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

RECOMMENDED MINIMUM PADS FOR D^{2}PAK: 3-Lead



Recommended Minimum Pads
Dimensions in Inches/(mm)